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Erratum: “Performing current versus voltage measurements of single-walled carbon nanotubes using scanning force microscopy” [Appl. Phys. Lett. 80, 1462 (2002)]

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Due to a production error, the affiliation of P. J. de Pablo and C. Gómez-Navarro appeared incorrectly. AIP apologizes for this error; the correct author affiliations appear above.

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